# Notice of References Cited Application/Control No. 10/701,192 Examiner Richard Bueker Applicatios/Patent Under Reexamination SELVAMANICKAM, VENKAT Page 1 of 2

### **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-3,303,320	02-1967	PAUL MULLER	219/121.15
	В	US-4,841,908	06-1989	Jacobson et al.	118/718
	С	US-4,888,202	12-1989	Murakami et al.	117/105
	D	US-5,227,363	07-1993	Furukawa et al.	505/473
	E	US-5,262,194	11-1993	Bischer et al.	427/9
	F	US-6,190,752	02-2001	Do et al.	428/141
	G	US-6,294,479	09-2001	Ebe et al.	438/758
	Н	US-2003/0054105	03-2003	Hammond et al.	427/294
	ı	US-2003/0193294	10-2003	Wahlin, Erik Karl Kristian	315/111.21
	J	US-2004/0168636	09-2004	Savvides et al.	118/723.0CB
	K	US-2004/0258851	12-2004	Selvamanickam et al.	427/551
	L	US-2004/0261708	12-2004	Selvamanickam et al.	118/718
	М	US-2004/0261707	12-2004	Selvamanickam et al.	118/718

# **FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 01-208456	08-1989	Japan	Nakatani	
	0	JP 03-013567	01-1991	Japan	Tsukamoto	
	Р	JP 06-192823	07-1994	Japan	Wakamoto	
	Q					
	R					
	s					
	Т					

## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Hammond, Thick film YBCO for Wires and Tapes: scale-up Issues and Cost Estimates; Advances in Superconductivity VIII Proc. 8th Int. Sump. Supercond. (ISS), Springer-Verlag, Tokyo, 1996.
	٧	
	w	
	х	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

### Application/Control No. Applicant(s)/Patent Under Reexamination 10/701,192 SELVAMANICKAM, VENKAT Notice of References Cited Art Unit Examiner Page 2 of 2 1763 Richard Bueker **U.S. PATENT DOCUMENTS** Document Number Date Classification Name Country Code-Number-Kind Code MM-YYYY 204/192.11 US-2005/0011747 01-2005 Selvamanickam et al. Α US-В US-С US-D Ε US-US-F US-G US-Н

### **FOREIGN PATENT DOCUMENTS**

	TOTALION FAILUI BOOGNETTO					
*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N				,	
	0					
	Р					
	Q					
	R					
	s					
	Т	,				

### **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)				
	U					
	>					
	V					
	X					

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

US-

US-

US-US-

US-

t

Κ

L

М